

Notice of References Cited	Application/Control No. 10/594,140	Applicant(s)/Patent Under Reexamination HAN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10-130733	05-1998	Japan	Akio Tosaka	C22C 38/08
	O	JP 06-017140	01-1994	Japan	Sakehide Senuma	C21D 9/48
	P	JP 2003-253378	02-2002	Japan	Atsushi Takahashi	C22C 38/00
	Q	JP 11-199991	07-1999	Japan	Okuda	C22C 38/08
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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